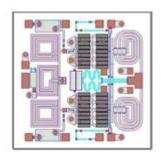


Applications

- · Commercial and military radar
- Communications
- Electronic Warfare



Product Features

Frequency Range: 0.1 – 3.0GHz
P_{SAT}: 41dBm at P_{IN} = 27dBm

P1dB: >34dBmPAE: >40%

Large Signal Gain: 14dBSmall Signal Gain: 22dB

IM3 @ 120mA POUT< 33dBm/tone: -30dBc

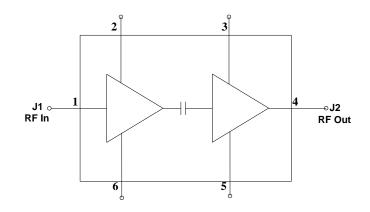
IM5 @ 120mA POUT< 33dBm/tone: -35dBc

• Bias: $V_D = 48V$, $I_{DQ} = 360mA$, $V_{G1} = -2.3V$ Typical, $V_{G2} = +21.7V$ Typical

· Wideband Flat Gain and Power

Chip Dimensions: 1.8 x 1.8 x 0.10 mm

Functional Block Diagram



General Description

TriQuint's TGA2216 is a wideband cascode amplifier fabricated on TriQuint's production 0.25um GaN on SiC process. The cascode configuration offers exceptional wideband performance as well as supporting 48V operation. The TGA2216 operates from 0.1 - 3.0GHz and provides 12W of saturated output power with 14dB of large signal gain and greater than 40% power-added efficiency.

The broadband performance supports both radar and communication applications across defense and commercial markets as well as electronic warfare. The TGA2216 is fully matched to 50Ω at both RF ports allowing for simple system integration. DC blocks are required on both RF ports and the drain voltage must be injected through an off chip bias-tee on the RF output port.

Lead-free and RoHS compliant.

Evaluation boards are available upon request.

Pad Configuration

Pad No.	Symbol
1	RF In, VG1
2, 6	V _{G1}
3, 5	V _{G2}
4	RF Out, V _D

Ordering Information

Part	ECCN	Description
TGA2216	EAR99	0.1 – 3.0GHz 12W GaN Power Amplifier

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Absolute Maximum Ratings

Parameter	Value		
Drain Voltage (V _D)	80V		
Gate Voltage Range (V _{G1})	-8 to 0V		
Gate Voltage Range (V _{G2})	0 to 40V		
Drain Current (I _D)	760mA		
Gate Current (I _{G1})	-5 to 5.6mA		
Gate Current (I _{G2})	-5 to 5.6mA		
Power Dissipation (P _{DISS}), 85°C	28W		
Input Power (P_{IN}), CW, 50 Ω , 85°C,	33dBm		
Input Power (P_{IN}), CW, VSWR 10:1, $V_D = 48V$, 85°C	30dBm		
Channel Temperature (T _{CH})	275°C		
Mounting Temperature (30 Seconds)	320°C		
Storage Temperature	-55 to 150°C		

Operation of this device outside the parameter ranges given above may cause permanent damage. These are stress ratings only, and functional operation of the device at these conditions is not implied.

Recommended Operating Conditions

Parameter	Value
Drain Voltage (V _D)	48V
Drain Current (I _{DQ})	360mA
Drain Current Under RF Drive (I _{D_Drive})	710mA
Gate Voltage (V _{G1})	-2.3V (Typ.)
Gate Voltage (V _{G2})	+21.7V (Typ.)

Electrical specifications are measured at specified test conditions. Specifications are not guaranteed over all recommended operating conditions.

Electrical Specifications

Test conditions unless otherwise noted: 25° C, $V_D = 48$ V, $I_{DQ} = 360$ mA, $V_{G1} = -2.3$ V Typical, $V_{G2} = +21.7$ V Typical

Parameter	Min	Typical	Max	Units
Operational Frequency Range	0.1		3.0	GHz
Small Signal Gain		22		dB
Input Return Loss		10 (mid band)		dB
Output Return Loss		10 (mid band)		dB
Output Power (Pin = 27dBm)		41		dBm
Power Added Efficiency (Pin = 27dBm)		> 40		%
Power @ 1dB Compression (P1dB)		> 34		dB
IM3 @ 120mA POUT/Tone < 33dBm		-30		dBc
IM5 @ 120mA Pout/Tone < 33dBm		-35		dBc
Small Signal Gain Temperature Coefficient		-0.02		dB/°C
Output Power Temperature Coefficient		-0.005		dBm/°C
Recommended Operating Voltage:	40	48	50	V



Thermal and Reliability Information

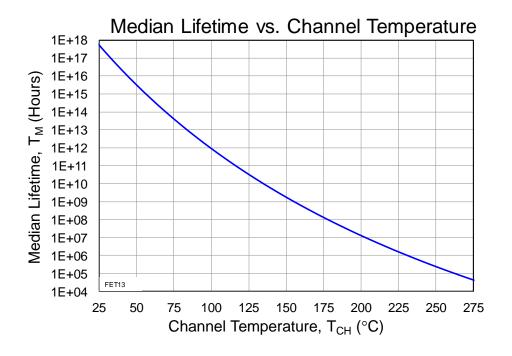
Parameter	Test Conditions	Value	Units
Thermal Resistance (θ _{JC}) ⁽¹⁾	$T_{\text{base}} = 85^{\circ}\text{C}, \ V_{\text{D}}^{(2)} = 40\text{V}, \ I_{\text{DQ}} = 360\text{mA}$	6.56	°C/W
Channel Temperature (T _{CH}) (Under RF drive)	$T_{\text{base}} = 85^{\circ}\text{C}, V_{D}^{(2)} = 40\text{V}, I_{D_Drive} = 635\text{mA}, Pout$	183	°C
Median Lifetime (T _M)	$= 40$ dBm, $P_{DISS} = 15$ W	6 x 10^8	Hrs
Thermal Resistance (θ _{JC}) ⁽¹⁾	$T_{\text{base}} = 85^{\circ}\text{C}, V_{\text{D}}^{(2)} = 48\text{V}, I_{\text{DQ}} = 360\text{mA},$	6.85	°C/W
Channel Temperature (T _{CH}) (Under RF drive)	$T_{\text{base}} = 85^{\circ}\text{C}, V_{\text{D}}^{(2)} = 48\text{V}, I_{\text{D_Drive}} = 675\text{mA}, Pout$	222	°C
Median Lifetime (T _M)	= 40.8dBm, P _{DISS} = 20W	1.99 x 10^6	Hrs

Notes:

- 1. Thermal resistance measured to back of carrier plate. MMIC mounted on 40 mils CuMo (80/20) carrier using 1.5 mil AuSn.
- 2. The drain voltage for Cascode amplifier transistor is $\frac{1}{2}$ of the V_{D}

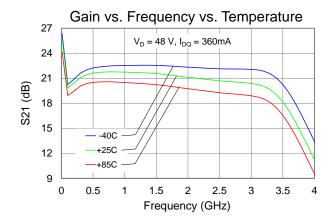
Median Lifetime

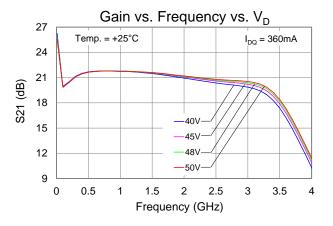
Test Conditions: $V_D = 40 \text{ V}$; Failure Criteria = 10% reduction in $I_{D \text{ MAX}}$

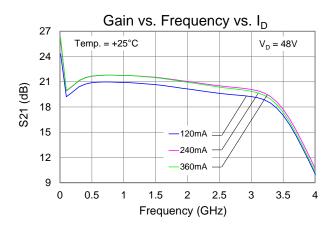


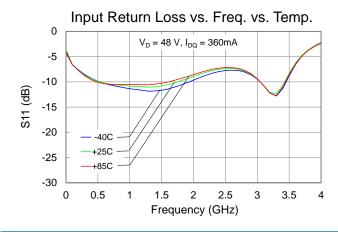


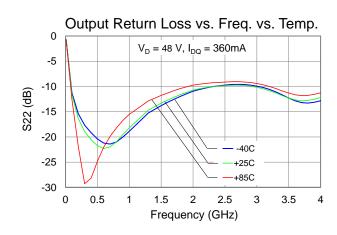
The plots reflect performance measured with an external coaxial bias tee and DC blocks (See application circuit on page 10)







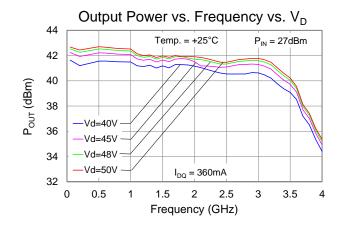


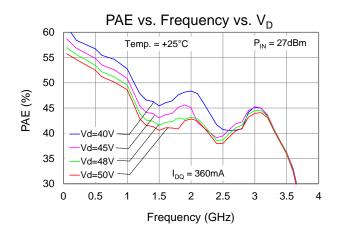


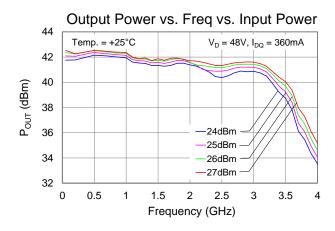
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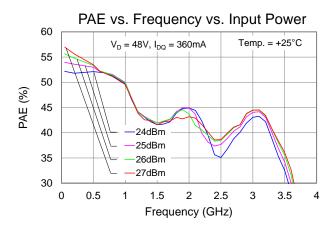


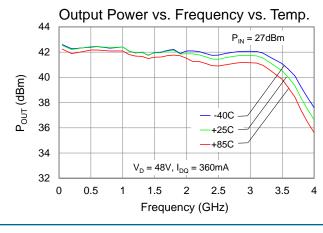
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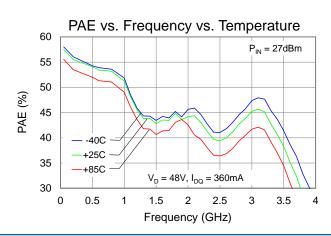








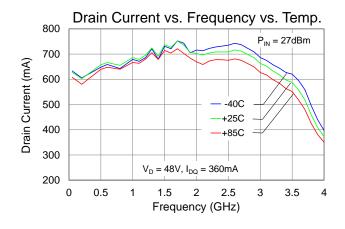


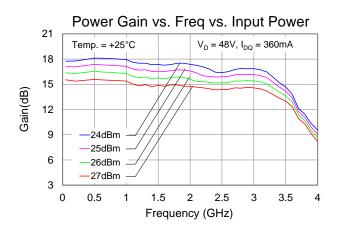


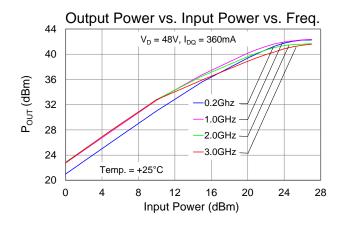
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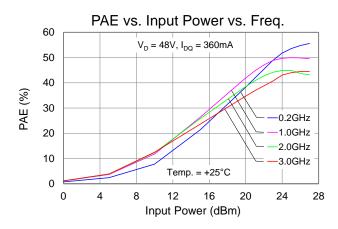


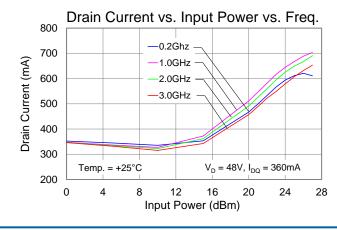
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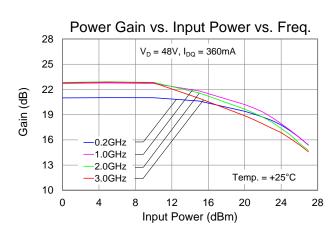








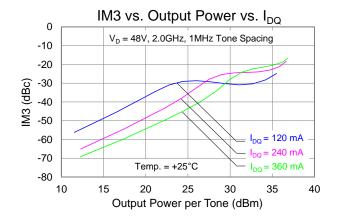


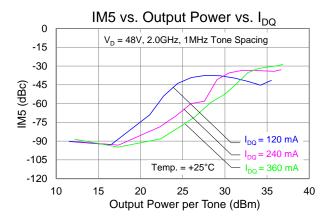


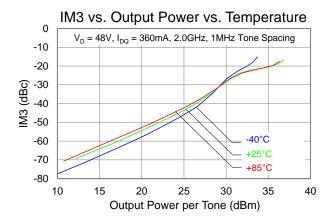
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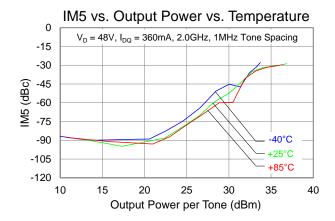


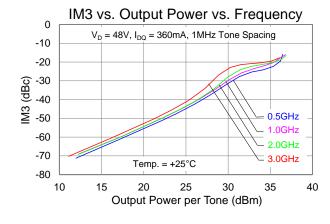
The plots reflect performance measured with an external coaxial bias tee and DC blocks (See application circuit on page 10)

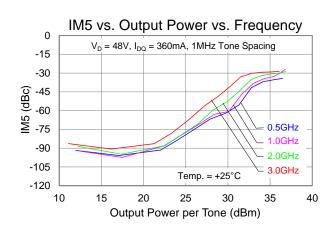






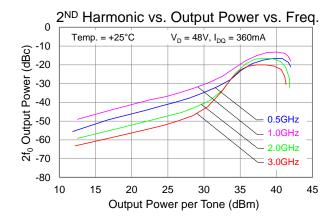


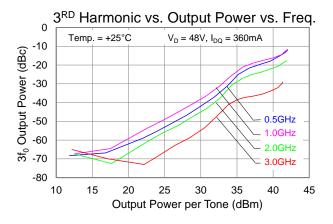


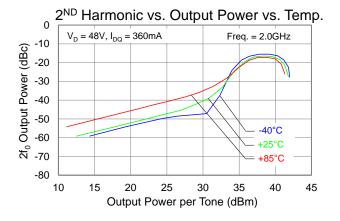


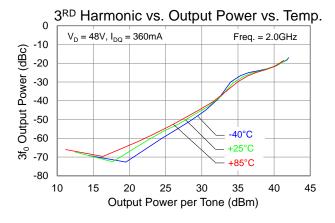


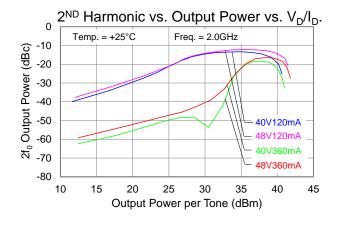
The plots reflect performance measured with an external coaxial bias tee and DC blocks (See application circuit on page 10)

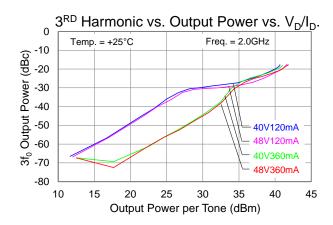






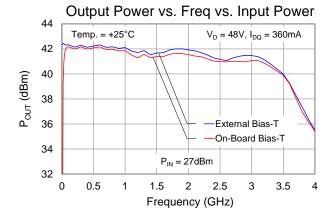


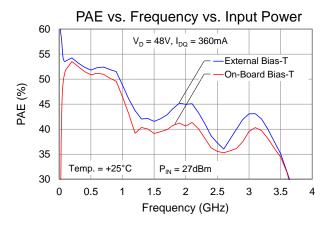






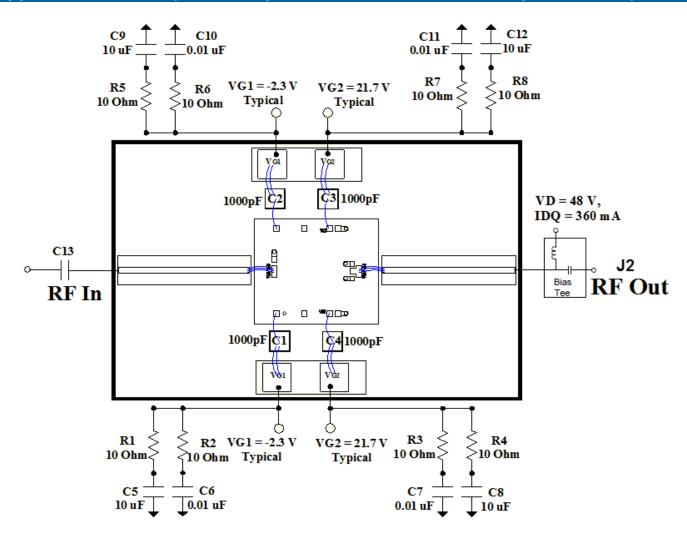
The plots below reflect performance measured between external bias tee and on-board bias tee (See application circuit on pages 10 and 12)







Application Circuit (Coaxial input DC block and coaxial output bias tee)



Notes:

- 1. Vg1 & Vg2 can be biased from either side (Top or Bottom.)
- 2. Coaxial input DC block (C13) is used for input port (RF In.)
- 3. External wide bandwidth Bias-Tee is used for output port (RF Out). VD is applied through the output Bias-Tee.

Bias-up Procedure

- 1. Set I_D limit to 720mA, $I_{G1\ \&}\ I_{G2}$ limit to 5mA
- 2. Set V_{G1} to -5.0V
- 3. Set V_{G2} to (VD/2) 2.7V or 48V/2 2.7V = 21.3V
- 4. Set VD +48V
- 5. Adjust V_{G1} more positive until I_{DQ} = 360mA ($V_{G1} \sim$ 2.3V Typical)
- 6. Adjust VG2 to (VD/2) + VG1; $(V_{G2} \sim 21.7V \text{ Typical})$
- 7. Apply RF signal

Bias-down Procedure

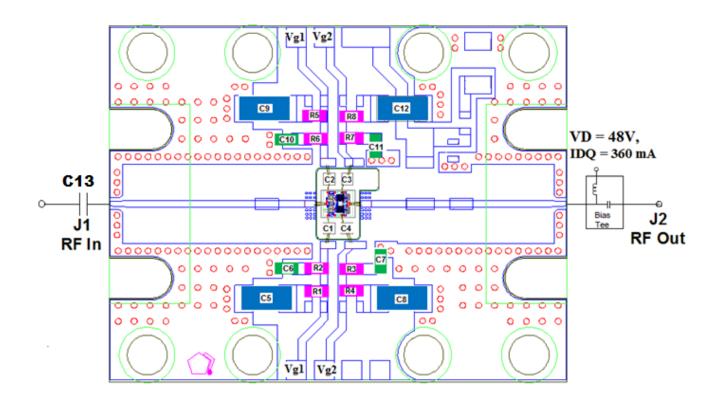
- 1. Turn off RF signal
- 2. Reduce V_{G1} to -5.0V. Ensure $I_{DQ} \sim 0 mA$
- 3. Reduce V_{G2} to 0V.
- 4. Set V_D to 0V
- 5. Turn off V_D supply
- 6. Turn off V_{G2} supply
- 7. Turn off V_{G1} supply

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Assembly Drawing (Coaxial input DC block and coaxial output bias tee)

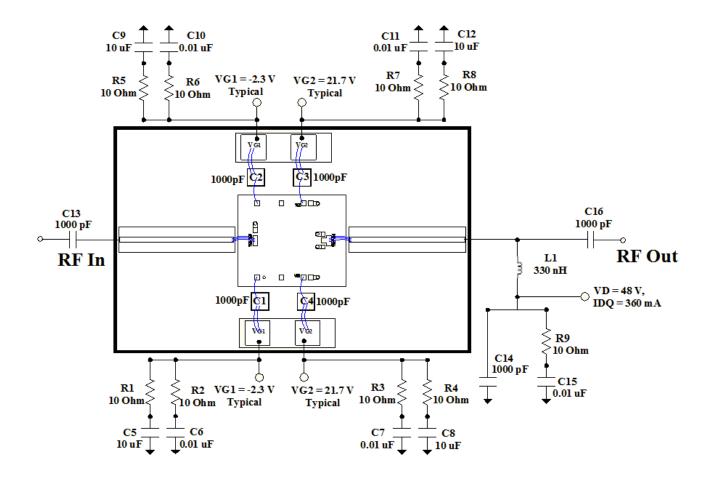


Bill of Materials

Reference Design	Value	Description	Manufacturer	Part Number
C1 – C4	1000pF	SLC, 50V	Various	
C5, C8, C9, C12	10uF	Cap, 1206, 50V, 10%, X7R	Various	
C6, C7, C10, C11	0.01uF	Cap, 0402, 50V, 10%, X7R	Various	
C13		DC Block	Various	
R1 – R8	10Ω	Res, 0402	Various	



Application Circuit (Option with board-level DC blocks and output bias tee)

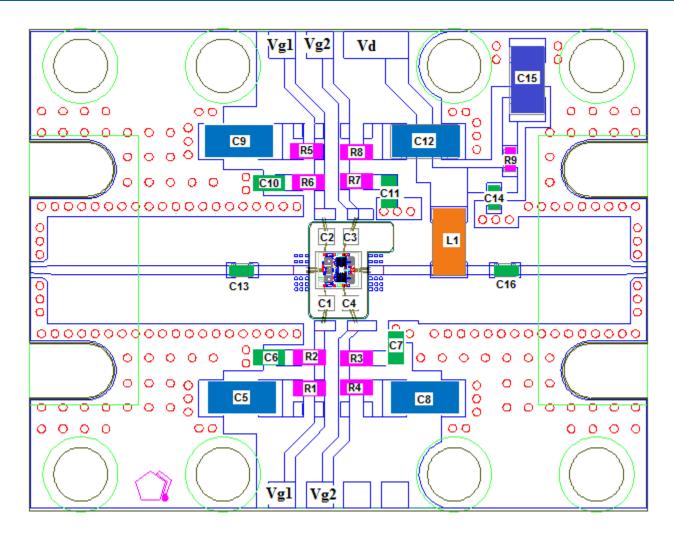


Notes:

- 1. Performance of the MMIC with surface mount DC blocks and bias tee components may be degraded relative to the coaxial option. These components should be optimized for the desired operational bandwidth.
- 2. V_{G1} & V_{G2} can be biased from either side (Top or Bottom.)



Evaluation Board Layout with On-Board DC Blocks and Output Bias-T Option

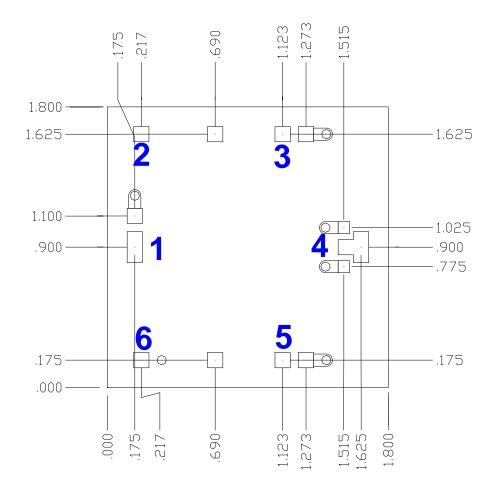


Bill of Materials For On-Board Bias-Tee

Reference Design	Value	Description	Manufacturer	Part Number
C13, C14, C16	1000pF	Cap, 0402, 100V, 10%, X7R	Various	
C15	0.01uF	Cap, 1206, 100V, 10%, X7R	Various	
L1	330nH	Ind, 1206, 100V, 10%, X7R	Various	
R9	10Ω	Res, 0402	Various	



Mechanical Drawing & Bond Pad Description



Unit: millimeters Thickness: 0.10

Die x, y size tolerance: ± -0.050

Chip edge to bond pad dimensions are shown to center of pad

Ground is backside of die

Bond Pad	Symbol	Pad Size	Description
1	RF In/ VG1	0.098 x 0.198	RF Input; VG1 gate voltage is present here, DC block is required.
2, 6	VG1	0.098 x 0.098	Gate voltage 1, bias network is required; see Application Circuit on pages 10 and 12 as an example.
3, 5	VG2	0.098 x 0.098	Gate voltage 2, bias network is required; see Application Circuit on pages 10 and 12 as an example.
4	RF Out/ VD	0.098 x 0.198	Output; Drain voltage, bias network is required; see Application Circuit on pages 10 and 12 as an example.







Assembly Notes

Component placement and adhesive attachment assembly notes:

- · Vacuum pencils and/or vacuum collets are the preferred method of pick up.
- · Air bridges must be avoided during placement.
- The force impact is critical during auto placement.
- Organic attachment (i.e. epoxy) can be used in low-power applications.
- Curing should be done in a convection oven; proper exhaust is a safety concern.

Reflow process assembly notes:

- Use AuSn (80/20) solder and limit exposure to temperatures above 300°C to 3-4 minutes, maximum.
- · An alloy station or conveyor furnace with reducing atmosphere should be used.
- · Do not use any kind of flux.
- Coefficient of thermal expansion matching is critical for long-term reliability.
- Devices must be stored in a dry nitrogen atmosphere.

Interconnect process assembly notes:

- Thermosonic ball bonding is the preferred interconnect technique.
- Force, time, and ultrasonic are critical parameters.
- · Aluminum wire should not be used.
- Devices with small pad sizes should be bonded with 0.0007-inch wire.





Product Compliance Information

ESD Sensitivity Ratings



Caution! ESD-Sensitive Device

ESD Rating: TBD Value: TBD

Test: Human Body Model (HBM)
Standard: JEDEC Standard JESD22-A114

ECCN

US Department of Commerce: EAR99

Solderability

This part is compliant with EU 2002/95/EC RoHS directive (Restrictions on the Use of Certain Hazardous Substances in Electrical and Electronic Equipment).

This product also has the following attributes:

- Lead Free
- Halogen Free (Chlorine, Bromine)
- Antimony Free
- TBBP-A (C₁₅H₁₂Br₄O₂) Free
- PFOS Free
- SVHC Free

Contact Information

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For technical questions and application information: Email: info-products@triquint.com

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